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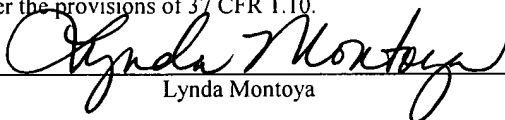
PATENT TRADEMARK OFFICE

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re United States Patent Application of:)	
)	
Applicant: Tischler, et al.)	Docket No.: 2771-161 CON
)	
Serial No.: Not Yet Assigned)	
)	
Date Filed: August 14, 2001)	
)	
Title: BULK SINGLE CRYSTAL)	
GALLIUM NITRIDE AND)	
METHOD OF MAKING SAME)	

EXPRESS MAIL CERTIFICATE

I hereby certify that I am mailing the attached documents to the Commissioner for Patents on the date specified, in an envelope addressed to the Commissioner for Patents, Washington, D.C., 20231 and Express Mailed under the provisions of 37 CFR 1.10.



Lynda Montoya

August 14, 2001

Date

EL831358355US

Express Mail Label Number

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

Pursuant to 37 C.F.R. §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449.

Documents AA to AY were previously submitted in the patent application (U.S. Patent Application No. 08/955,168); copies of such documents were previously submitted in such application.

It is respectfully requested that the information listed on the attached PTO-1449 be expressly considered during the prosecution of this application, and that the reference(s) be made of record and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,



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FORM PTO-1449 US Dept. of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO. 2771-161 CON		SERIAL NO. Not Yet Assigned		
INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)		APPLICANT Tischler, et al.				
		FILING DATE August 14, 2001		GROUP		
U.S. PATENT DOCUMENTS						
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	4,727,047	2/23/88	Bozler et al.	437	089
	AB	4,931,132	6/5/90	Aspnes et al.		
	AC	4,622,083	11/11/86	Shih		
	AD	5,334,277	8/94	Nakamura	117	102
	AE	3,598,526	8/10/71	Humi et al.	23	192
	AF	3,634,149	1/11/72	Knippenberg	148	175
	AG	3,326,820	6/20/67	Cuomo et al.	252	478
	AH	5,954,874	9/21/99	Hunter	117	84
	AI	5,919,305	4/6/99	Solomon	117	90
	AJ	5,846,844	12/8/98	Akasaki et al.	437	21
	AK	5,385,862	1/31/95	Moustakas	437	107
	AL	3,829,556	8/13/74	Logan et al.	423	409
	AM	5,146,465	9/8/92	Khan et al.	372	45
	AN	5,433,169	7/18/95	Nakamura	117	102
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AO	JP56-59700A	10/17/79	JAPAN		
	AP	62183399	6/22/87	JAPAN		
OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)						
	AQ	Derwent Abstract of JP 56-59700A; Matsushita Elec Ind Co.; "Gallium Nitride Thin Single Crystal Film"; 1979				
	AR	"Defect reduction in GaAs epitaxial layers using a GaAsP-InGaAs strained-layer superlattice," Tischler et al., Appl. Phys. Lett. 46(3), pp. 294-296 (1985)				
	AS	"GaN, AlN, and InN: A review," Striete, S., and Morkoc, J. Vac. Sci. Technol. B 10 (4), 1237-1266 (1992)				
	AT	"Current Status of GaN and Related Compounds as Wide-Gap Semiconductors," Matsuoka, T., J. Crystal Growth 124, 433-438 (1992)				
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EXAMINER				DATE CONSIDERED		

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AU	5,239,188	8/24/93	Takeuchi et al.	257	76	
	AV	5,006,914	4/9/91	Beetz, Jr.	357	61	
	AW	5,373,171	12/13/94	Imai et al.	257	77	
	AX	3,922,703	11/25/75	Pankove	357	17	
	AY	4,985,742	12/15/91	Pankove	357	34	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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